

EG Talc C45

Sedigraph Particle size distribution test

17%	7.0 μm Max.	40 ± 3.00 μm
Cumulative Fi	ner Mass Percent vs. Diam	<u>ieter</u>
	Cumulative Fi	Cumulative Finer Mass Percent vs. Diam

D98: 40 μm D50: 7 μm

Finer than 2 µm: 17%

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